

Applicant: Koichi Takiguchi, et al.
 Serial No.: 10/614,637
 Filing Date: 07/07/2003
 For: CHARACTERISTIC ADJUSTMENT METHOD OF MULTISTAGE MACH-ZEHNDER INTERFEROMETER TYPE OPTICAL CIRCUIT

Confirmation No.: 7656
 Att'y Docket No.: 14321.55
 Group: 2874



INFORMATION DISCLOSURE CITATIONS MADE BY APPLICANT

U.S. Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Issue Date</u>	<u>Name</u>
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Foreign Patent Documents

<u>Examiner Initial*</u>	<u>Document Number</u>	<u>Publication Date</u>	<u>Country or Patent Office</u>	<u>Translation</u>
<u>SP</u> 1	JP 7209090	11/08/1995	Japan	Abstract only

Other Documents (including author, title, pertinent pages, etc.)

Examiner Initial*

- SP 2 OFFREIN, B. J., et al., "Adaptive Gain Equalizer in High-Index-Contrast SiON Technology," *IEEE Photonics Technology Letters*, IEEE Inc., New York, US, Vol. 12, No. 5, May 2000, pp. 504-506
- SP 3 WACOGNE, B., et al., "Double Security Level in a Telecommunication System Based on Phase Coding and False Data Transmission," *Journal of Lightwave Technology*, IEEE, New York, US, Vol. 14, No. 5, May 1996, pp. 665-670
- SP 4 TAKIGUCHI, K., et al., "Variable Group-Delay Dispersion Equalizer Using Lattice-Form Programmable Optical Filter on Planar Lightwave Circuit," *IEEE Journal of Selected Topics in Quantum Electronics*, IEEE Service Center, US, Vol. 2, No. 2, June 1996, pp. 270-276
- SP 5 TAKADA, K., et al., "Measurement of phase error distributions in silica-based arrayed-waveguide grating multiplexers by using Fourier transform spectroscopy," *Electronic Letters*, IEE Stevenage, GB, Vol. 30, No. 20, 29 September 1994, pp. 1671-1672

Examiner: Sung Park Date Considered: 2/18/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609, draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Sheet 2 of 2
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References Cited by Applicants

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Examiner:

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Date Considered:

2/18/05

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Applicant: Koichi Takiguchi et al.
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 Filing Date: July 7, 2003
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U.S. Patent Documents

Examiner <u>Initial*</u>	Document <u>Number</u>	Issue <u>Date</u>	<u>Name</u>
<u>SP</u> 1	5,596,661	01/21/1997	Henry et al.

Foreign Patent Documents

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Other Documents

(including author, title, pertinent pages, etc.)

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- SP 2 Koichi Takiguchi et al., *Planar Lightwave Circuit Optical Dispersion Equalizer*, IEEE Photonics Technology Letters, Vol. 6, No. 1, January 1994, pp. 86-88.
- SP 3 S. Suzuki et al., *Low-Loss Integrated-Optic Dynamic Chromatic Dispersion Compensators Using Lattice-Form Planar Lightwave Circuits*, Tuesday Afternoon, Vol. 1, OFC 2003, pp. 176-177.
- SP 4 K. Takiguchi et al., *Method for Adjusting Lattice-Form Optical Devices and Its Use in Realising Low-Loss Variable Chromatic Dispersion Compensator*, Electronics Letters, Vol. 39, No. 4, February 20, 2003.

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